

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application)	<u>PATENT APPLICATION</u>
)	
Inventor(s):	Cleeves et al.)
)
) Art Unit: 2814
Application No.:	10/681,509)
)
Filed:	October 7, 2003) Examiner: Howard Weiss
)
Title:	UNIFORM SEEDING TO) Atty Docket No. SAND-01135US0
	CONTROL GRAIN AND) (formerly MA-108)
	DEFECT DENSITY OF)
	CRYSTALLIZED SILICON)
	FOR USE IN SUB-MICRON))
	THIN FILM TRANSISTORS))
) <u>Customer No. 64948</u>

RESPONSE TO OFFICE ACTION UNDER 37 C.F.R. § 1.111 TO ACCOMPANY REQUEST
FOR CONTINUED EXAMINATION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

To the Commissioner:

Applicants request continued examination under 37 CFR 1.114. The amended claims and remarks included herein constitute the required submission.

Amendments to the claims begin on page 2 of this paper.

Remarks begin on Page 11 of this paper.